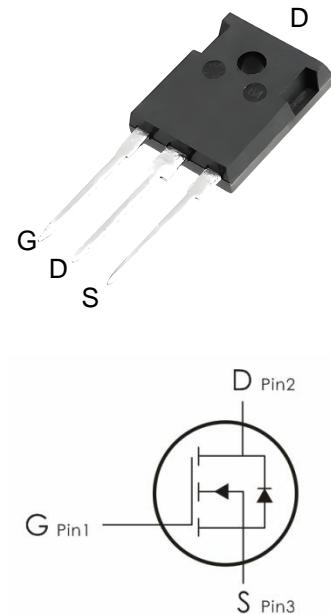


Description:

This N-Channel MOSFET uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications.

Features:

- 1) $V_{DS}=60V, I_D=130A, R_{DS(ON)} < 5.5m\ \Omega @ V_{GS}=10V$ (Typ: $4.9m\ \Omega$)
- 2) Low gate charge.
- 3) Green device available.
- 4) Advanced high cell density trench technology for ultra low $R_{DS(ON)}$.
- 5) Excellent package for good heat dissipation.
- 6) Fast Recovery Body Diode



Package Marking and Ordering Information:

| Part NO. | Marking | Package | Packing |
|-----------|---------|---------|-------------|
| GE5R5NG-H | E5R5N-H | TO- 247 | 30 pcs/Tube |

Absolute Maximum Ratings: ($T_C=25^\circ C$ unless otherwise noted)

| Symbol | Parameter | Ratings | Units |
|----------------|--|----------|------------|
| V_{DS} | Drain-Source Voltage | 60 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| I_D | Continuous Drain Current ¹ | 130 | A |
| | Continuous Drain Current- $T_C=100^\circ C$ ¹ | 91 | |
| I_{DM} | Pulsed Drain Current ² | 520 | |
| P_D | Power Dissipation | 125 | W |
| E_{AS} | Single pulse avalanche energy ³ | 272 | mJ |
| T_J, T_{STG} | Operating and Storage Junction Temperature Range | -55-+150 | $^\circ C$ |

Thermal Characteristics:

| Symbol | Parameter | Max | Units |
|-----------------|--------------------------------------|-----|--------------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | 1 | $^\circ C/W$ |

Electrical Characteristics: ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|---|---|---|--|------|-----------|------------------|
| Off Characteristics | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\ \mu\text{A}$ | 60 | --- | --- | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{GS}=0V, V_{DS}=60V$ | --- | --- | 10 | μA |
| I_{GSS} | Gate-Source Leakage Current | $V_{GS}=\pm 20V, V_{DS}=0A$ | --- | --- | ± 100 | nA |
| On Characteristics | | | | | | |
| $V_{GS(th)}$ | Gate-Source Threshold Voltage | $V_{GS}=V_{DS}, I_D=250\ \mu\text{A}$ | 2 | 2.8 | 4 | V |
| $R_{DS(on)}$ | Drain-Source On Resistance ¹ | $V_{GS}=10V, I_D=20A$ | --- | 4.9 | 5.5 | $\text{m}\Omega$ |
| Dynamic Characteristics | | | | | | |
| C_{iss} | Input Capacitance | $V_{DS}=25V, V_{GS}=0V, f=1\text{MHz}$ | --- | 5100 | --- | pF |
| C_{oss} | Output Capacitance | | --- | 495 | -- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 269 | --- | |
| Switching Characteristics | | | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | $V_{DS}=30V, I_D=30A,$ $R_{ENG}=1.8\ \Omega, V_{GS}=10V$ | --- | 11 | --- | ns |
| t_r | Rise Time | | --- | 8 | --- | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | | --- | 49 | --- | ns |
| t_f | Fall Time | | --- | 14 | --- | ns |
| Q_g | Total Gate Charge | | $V_{GS}=10V, V_{DS}=30V,$ $I_D=30A$ | --- | 103 | --- |
| Q_{gs} | Gate-Source Charge | --- | | 13 | --- | nC |
| Q_{gd} | Gate-Drain "Miller" Charge | --- | | 31.5 | --- | nC |
| Drain-Source Diode Characteristics | | | | | | |
| V_{SD} | Diode Forward Voltage | $V_{GS}=0V, I_{SD}=30A$ | --- | --- | 1.2 | V |
| I_S | Continuous Drain Current | $V_D=V_G=0V$ | --- | --- | 108 | A |
| I_{SM} | Pulsed Drain Current | | --- | --- | 433 | A |
| T_{rr} | Reverse Recovery Time | $I_F=30A, T_J=25^\circ\text{C}$ | --- | 26 | --- | ns |
| Q_{rr} | Reverse Recovery Charge | $di/dt=100A/\mu\text{s}$ | --- | 47 | --- | nC |

Notes:

1. Computed continuous current assumes the condition of $T_{j,Max}$ while the actual continuous current depends on the thermal & electro-mechanical application board design
2. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
3. EAS condition : $T_J=25^{\circ}C, V_{DD}=30V, V_G=10V, L=0.5mH$
4. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$

Test Circuit

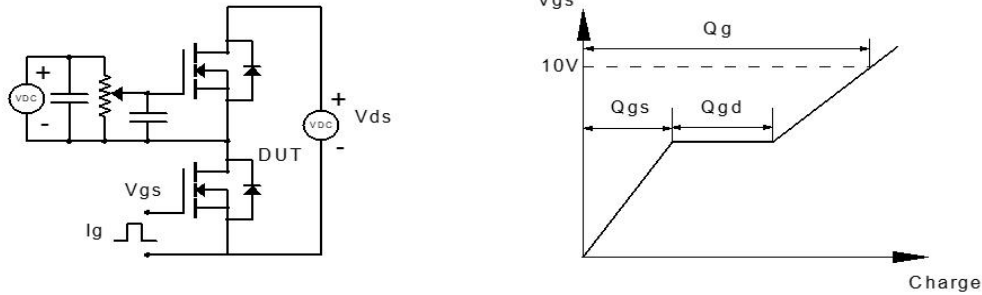


Figure 1: Gate Charge Test Circuit & Waveform

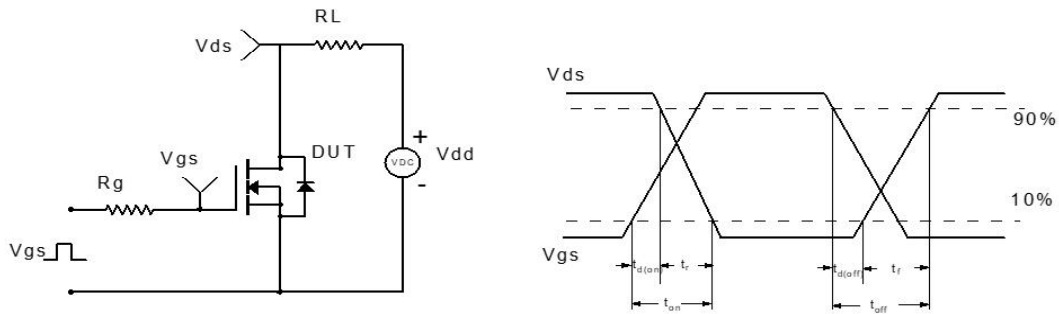


Figure 2: Resistive Switching Test Circuit & Waveform

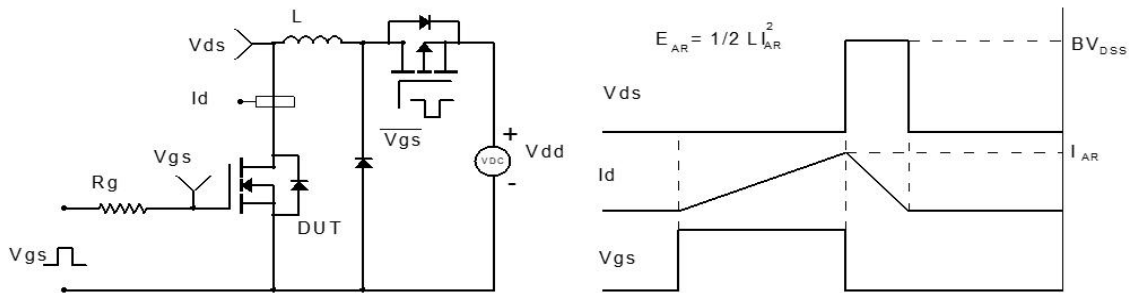


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

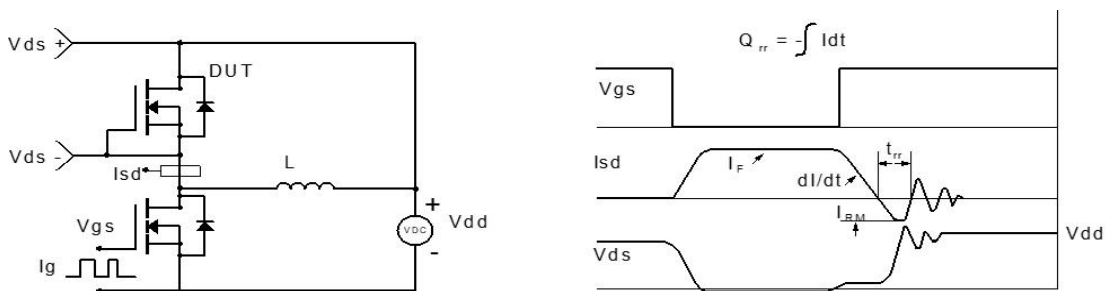
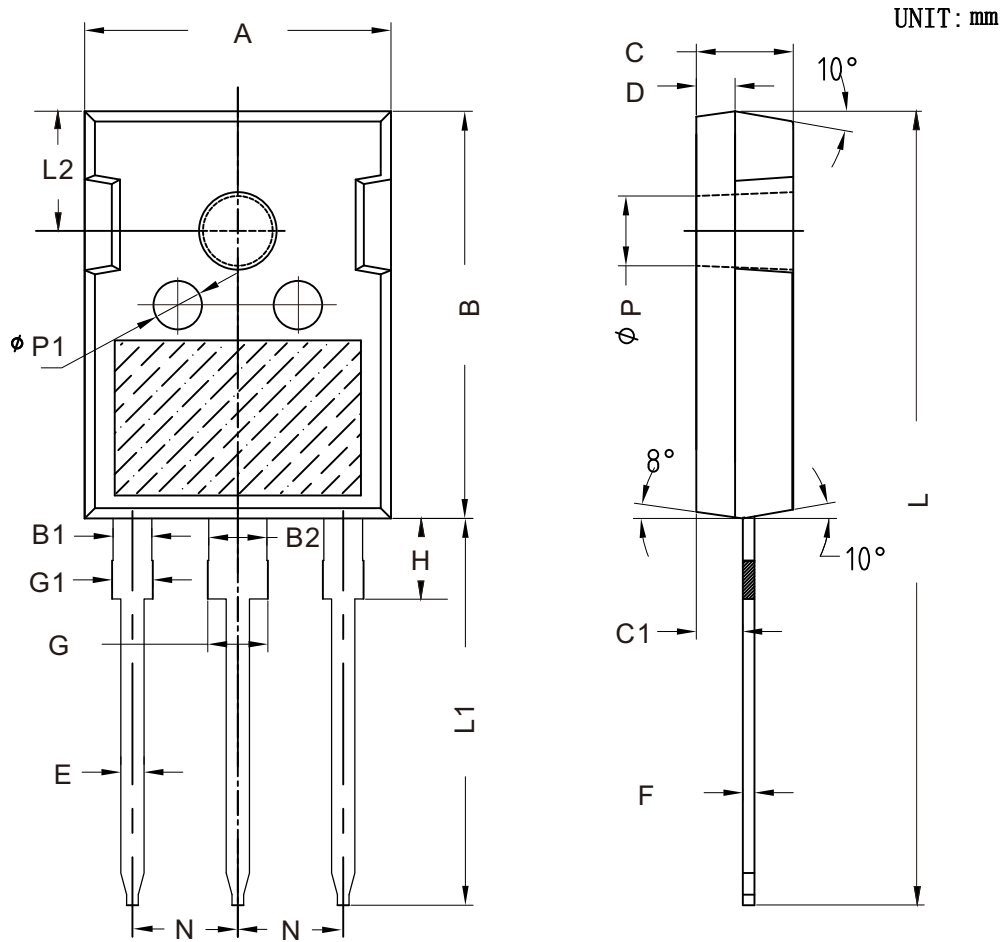


Figure 4: Diode Recovery Test Circuit & Waveform

TO-247 Package Information:



| Symbol | Millimeters | | Symbol | Millimeters | |
|--------|-------------|------|--------|-------------|------|
| | Min. | Max. | | Min. | Max. |
| A | 15.6 | 16.0 | G | 2.90 | 3.30 |
| B | 19.9 | 21.2 | G1 | 1.90 | 2.30 |
| B1 | 1.80 | 2.20 | H | 3.90 | 4.30 |
| B2 | 2.80 | 3.20 | L | 40.5 | 41.4 |
| C | 4.80 | 5.20 | L1 | 19.7 | 20.2 |
| C1 | 2.20 | 2.60 | L2 | 6.04 | 6.30 |
| D | 1.90 | 2.10 | N | 5.30 | 5.68 |
| E | 1.00 | 1.40 | ØP | 3.40 | 3.80 |
| F | 0.50 | 0.70 | ØP1 | 2.20 | 2.50 |

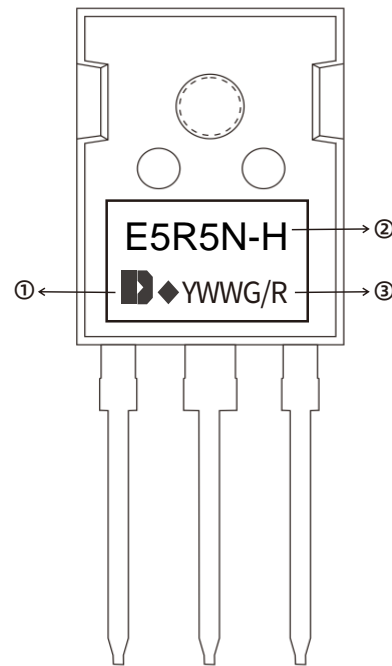
Marking Information:

- ①. Doingter LOGO
- ②. Part NO.
- ③. Date Code(YWWG / R)

Y : Year Code , last digit of the year

WW : Week Code(01-53)

G/R : G(Green) /R(Lead Free)



Previous Version

| Version | Date | Subjects (major changes since last revision) |
|---------|------------|--|
| 1.0 | 2026-01-22 | Release of final version |

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